Contents

Product Portfolio

Product	Range	V_{CC} Range (V)			Speed (ns)	Power Dissipation					
						Operating I_{CC}, (mA)				Standby, I_{SB2} (µA)	
						f = 1 MHz		f = f_{max}			
		Min	Typ[1]	Max		Typ[1]	Max	Typ[1]	Max	Typ[1]	Max
CY62157ELL	Industrial	4.5	5.0	5.5	45	1.8	3	18	25	2	8
CY62157ELL	Automotive	4.5	5.0	5.5	55	1.8	4	18	35	2	30

Pin Configurations

Figure 1. 44-pin TSOP II pinout [2, 3]

Top View

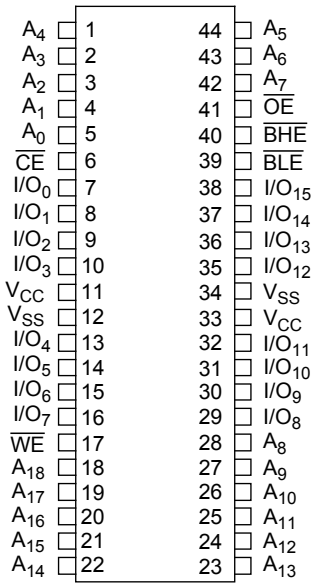
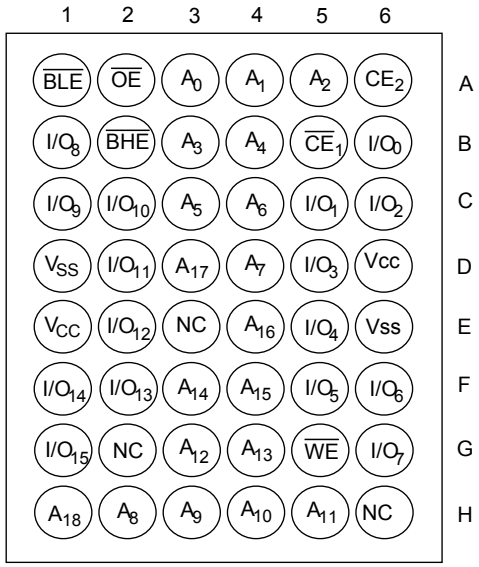


Figure 2. 48-ball VFBGA pinout [2]

Top View



Notes
1. Typical values are included for reference only and are not guaranteed or tested. Typical values are measured at $V_{CC} = V_{CC(typ)}$, T_A = 25 °C.
2. NC pins are not connected on the die.
3. The 44-pin TSOP II package has only one chip enable ($\overline{CE}$) pin.

Maximum Ratings

Exceeding maximum ratings may shorten the useful life of the device. User guidelines are not tested.

Storage Temperature ..... –65 °C to + 150 °C

Ambient Temperature with Power Applied ..... –55 °C to + 125 °C

Supply Voltage to Ground Potential .....–0.5 V to 6.0 V

DC Voltage Applied to Outputs in High Z State [4, 5] .....–0.5 V to 6.0 V

DC Input Voltage [4, 5] .....–0.5 V to 6.0 V

Output Current into Outputs (LOW) .....20 mA

Static Discharge Voltage (MIL-STD-883, Method 3015) .....> 2001 V

Latch up Current .....> 200 mA

Operating Range

Device	Range	Ambient Temperature	V_{CC}[6]
CY62157ELL	Industrial	–40 °C to +85 °C	4.5 V to 5.5 V
	Automotive	–40 °C to +125 °C	

Electrical Characteristics

Over the Operating Range

Parameter	Description	Test Conditions		45 ns (Industrial)			55 ns (Automotive)			Unit
				Min	Typ[7]	Max	Min	Typ[7]	Max	
V_{OH}	Output HIGH Voltage	V_{CC} = 4.5 V	I_{OH} = –1 mA	2.4	–	–	2.4	–	–	V
		V_{CC} = 5.5 V	I_{OH} = –0.1 mA	–	–	3.4 [8]	–	–	3.4 [8]	
V_{OL}	Output LOW Voltage	I_{OL} = 2.1 mA		–	–	0.4	–	–	0.4	V
V_{IH}	Input HIGH Voltage	V_{CC} = 4.5 V to 5.5 V		2.2	–	V_{CC} + 0.5	2.2	–	V_{CC} + 0.5	V
V_{IL}	Input LOW Voltage	V_{CC} = 4.5 V to 5.5 V		–0.5	–	0.8	–0.5	–	0.8	V
I_{IX}	Input Leakage Current	GND ≤ V_I ≤ V_{CC}		–1	–	+1	–4	–	+4	µA
I_{OZ}	Output Leakage Current	GND ≤ V_O ≤ V_{CC}, Output Disabled		–1	–	+1	–4	–	+4	µA
I_{CC}	V_{CC} Operating Supply Current	f = f_{max} = 1/t_{RC}	V_{CC} = $V_{CC(max)}$, I_{OUT} = 0 mA, CMOS levels	–	18	25	–	18	35	mA
		f = 1 MHz		–	1.8	3	–	1.8	4	
I_{SB1} [9]	Automatic CE Power Down Current – CMOS Inputs	$\overline{CE_1}$ ≥ V_{CC} – 0.2 V or CE_2 ≤ 0.2 V or ($\overline{BHE}$ and $\overline{BLE}$) ≥ V_{CC} – 0.2 V, V_{IN} ≥ V_{CC} – 0.2 V, V_{IN} ≤ 0.2 V, f = f_{max} (Address and Data Only), f = 0 ($\overline{OE}$ and $\overline{WE}$), V_{CC} = $V_{CC(max)}$		–	2	8	–	2	30	µA
I_{SB2} [9]	Automatic CE Power Down Current – CMOS Inputs	$\overline{CE_1}$ ≥ V_{CC} – 0.2 V or CE_2 ≤ 0.2 V or ($\overline{BHE}$ and $\overline{BLE}$) ≥ V_{CC} – 0.2 V, V_{IN} ≥ V_{CC} – 0.2 V or V_{IN} ≤ 0.2 V, f = 0, V_{CC} = $V_{CC(max)}$		–	2	8	–	2	30	µA

Notes

4. $V_{IL(min)}$ = –2.0 V for pulse durations less than 20 ns for I < 30 mA.
5. $V_{IH(max)}$ = V_{CC} + 0.75 V for pulse durations less than 20 ns.
6. Full device AC operation assumes a 100 µs ramp time from 0 to V_{CC}(min) and 200 µs wait time after V_{CC} stabilization.
7. Typical values are included for reference only and are not guaranteed or tested. Typical values are measured at V_{CC} = $V_{CC(typ)}$, T_A = 25 °C.
8. Please note that the maximum V_{OH} limit doesnot exceed minimum CMOS V_{IH} of 3.5 V. If you are interfacing this SRAM with 5 V legacy processors that require a minimum V_{IH} of 3.5V, please refer to Application Note AN6081 for technical details and options you may consider.
9. Chip enables ($\overline{CE_1}$ and CE_2) and byte enables ($\overline{BHE}$ and $\overline{BLE}$) need to be tied to CMOS levels to meet the I_{SB1} / I_{SB2} / I_{CCDR} spec. Other inputs can be left floating.

Capacitance

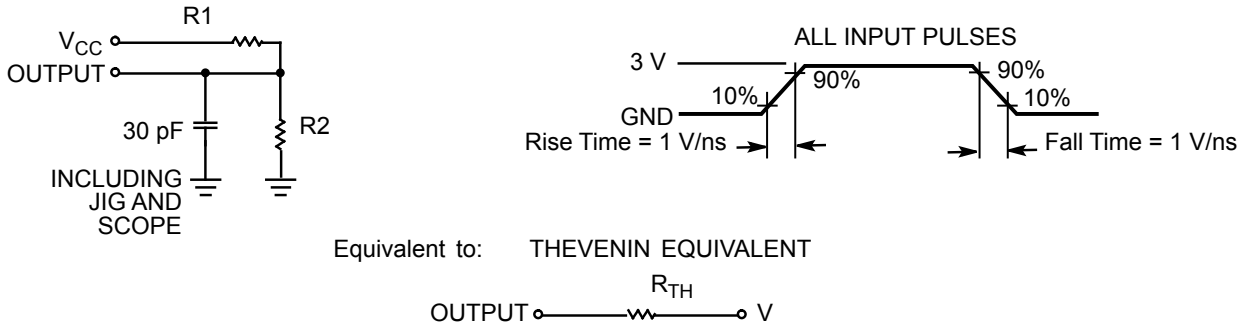
Parameter [10]	Description	Test Conditions	Max	Unit
C_{IN}	Input capacitance	T_A = 25 °C, f = 1 MHz, V_{CC} = $V_{CC(typ)}$	10	pF
C_{OUT}	Output capacitance		10	pF

Thermal Resistance

Parameter [10]	Description	Test Conditions	44-pin TSOP II	48-ball VFBGA	Unit
Θ_{JA}	Thermal resistance (junction to ambient)	Still Air, soldered on a 3 × 4.5 inch, two-layer printed circuit board	77	72	°C/W
Θ_{JC}	Thermal resistance (junction to case)		13	8.86	°C/W

AC Test Loads and Waveforms

Figure 3. AC Test Loads and Waveforms



Parameters	Values	Unit
R1	1800	Ω
R2	990	Ω
R_{TH}	639	Ω
V_{TH}	1.77	V

Note
10. Tested initially and after any design or process changes that may affect these parameters.

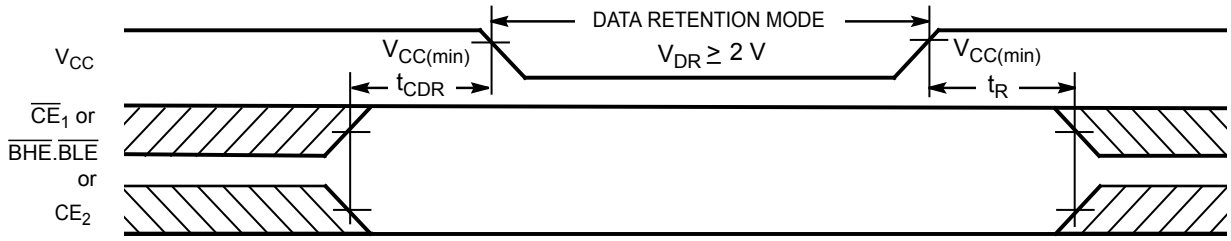
Data Retention Characteristics

Over the Operating Range

Parameter	Description	Conditions		Min	Typ [11]	Max	Unit
V_{DR}	V_{CC} for Data Retention			2	–	–	V
I_{CCDR}[12]	Data Retention Current	V_{CC} = 2 V, $\overline{CE_1} \geq V_{CC} - 0.2$ V or $CE_2 \leq 0.2$ V or ($\overline{BHE}$ and $\overline{BLE}$) $\geq V_{CC} - 0.2$ V, $V_{IN} \geq V_{CC} - 0.2$ V or $V_{IN} \leq 0.2$ V	Industrial	–	–	8	µA
			Automotive	–	–	30	
t_{CDR} [13]	Chip Deselect to Data Retention Time			0	–	–	ns
t_R [14]	Operation Recovery Time		CY62157ELL-45	45	–	–	ns
			CY62157ELL-55	55	–	–	

Data Retention Waveform

Figure 4. Data Retention Waveform [15]



Notes
11. Typical values are included for reference only and are not guaranteed or tested. Typical values are measured at $V_{CC} = V_{CC(typ)}$, T_A = 25 °C.
12. Chip enables ($\overline{CE_1}$ and CE_2) and byte enables ($\overline{BHE}$ and $\overline{BLE}$) need to be tied to CMOS levels to meet the I_{SB1} / I_{SB2} / I_{CCDR} spec. Other inputs can be left floating.
13. Tested initially and after any design or process changes that may affect these parameters.
14. Full device operation requires linear V_{CC} ramp from V_{DR} to $V_{CC(min)} \geq 100$ µs or stable at $V_{CC(min)} \geq 100$ µs.
15. $\overline{BHE}.\overline{BLE}$ is the AND of both $\overline{BHE}$ and $\overline{BLE}$. Deselect the chip by either disabling chip enable signals or by disabling both $\overline{BHE}$ and $\overline{BLE}$.

Switching Characteristics

Over the Operating Range

Parameter [16, 17]	Description	45 ns (Industrial)		55 ns (Automotive)		Unit
		Min	Max	Min	Max	
Read Cycle						
t_{RC}	Read Cycle Time	45	–	55	–	ns
t_{AA}	Address to Data Valid	–	45	–	55	ns
t_{OHA}	Data Hold from Address Change	10	–	10	–	ns
t_{ACE}	$\overline{CE}_1$ LOW and CE_2 HIGH to Data Valid	–	45	–	55	ns
t_{DOE}	$\overline{OE}$ LOW to Data Valid	–	22	–	25	ns
t_{LZOE}	$\overline{OE}$ LOW to Low Z[18]	5	–	5	–	ns
t_{HZOE}	$\overline{OE}$ HIGH to High Z[18, 19]	–	18	–	20	ns
t_{LZCE}	$\overline{CE}_1$ LOW and CE_2 HIGH to Low Z[18]	10	–	10	–	ns
t_{HZCE}	$\overline{CE}_1$ HIGH and CE_2 LOW to High Z[18, 19]	–	18	–	20	ns
t_{PU}	$\overline{CE}_1$ LOW and CE_2 HIGH to Power Up	0	–	0	–	ns
t_{PD}	$\overline{CE}_1$ HIGH and CE_2 LOW to Power Down	–	45	–	55	ns
t_{DBE}	$\overline{BLE}$/$\overline{BHE}$ LOW to Data Valid	–	45	–	55	ns
t_{LZBE}	$\overline{BLE}$/$\overline{BHE}$ LOW to Low Z[18]	10	–	10	–	ns
t_{HZBE}	$\overline{BLE}$/$\overline{BHE}$ HIGH to High Z[18, 19]	–	18	–	20	ns
Write Cycle[20]						
t_{WC}	Write Cycle Time	45	–	55	–	ns
t_{SCE}	$\overline{CE}_1$ LOW and CE_2 HIGH to Write End	35	–	40	–	ns
t_{AW}	Address Setup to Write End	35	–	40	–	ns
t_{HA}	Address Hold from Write End	0	–	0	–	ns
t_{SA}	Address Setup to Write Start	0	–	0	–	ns
t_{PWE}	$\overline{WE}$ Pulse Width	35	–	40	–	ns
t_{BW}	$\overline{BLE}$/$\overline{BHE}$ LOW to Write End	35	–	40	–	ns
t_{SD}	Data Setup to Write End	25	–	25	–	ns
t_{HD}	Data Hold from Write End	0	–	0	–	ns
t_{HZWE}	$\overline{WE}$ LOW to High Z[18, 19]	–	18	–	20	ns
t_{LZWE}	$\overline{WE}$ HIGH to Low Z[18]	10	–	10	–	ns

Notes

16. Test conditions for all parameters other than tri-state parameters assume signal transition time of 3 ns or less, timing reference levels of $V_{CC(typ)}/2$, input pulse levels of 0 to $V_{CC(typ)}$, and output loading of the specified I_{OL}/I_{OH} as shown in the AC Test Loads and Waveforms on page 5.
17. In an earlier revision of this device, under a specific application condition, READ and WRITE operations were limited to switching of the byte enable and/or chip enable signals as described in the Application Notes AN13842 and AN66311. However, the issue has been fixed and in production now, and hence, these Application Notes are no longer applicable. They are available for download on our website as they contain information on the date code of the parts, beyond which the fix has been in production. .
18. At any temperature and voltage condition, t_{HZCE} is less than t_{LZCE}, t_{HZBE} is less than t_{LZBE}, t_{HZOE} is less than t_{LZOE}, and t_{HZWE} is less than t_{LZWE} for any device.
19. t_{HZOE}, t_{HZCE}, t_{HZBE}, and t_{HZWE} transitions are measured when the outputs enter a high impedance state.
20. The internal write time of the memory is defined by the overlap of $\overline{WE}$, $\overline{CE}_1 = V_{IL}$, $\overline{BHE}$, $\overline{BLE}$, or both = V_{IL}, and $CE_2 = V_{IH}$. All signals must be active to initiate a write and any of these signals can terminate a write by going inactive. The data input setup and hold timing must be referenced to the edge of the signal that terminates the write.

Switching Waveforms

Figure 5. Read Cycle No. 1 (Address Transition Controlled) [21, 22]

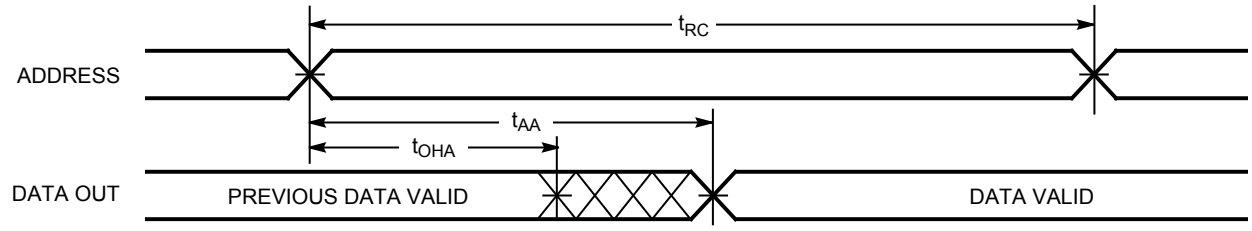
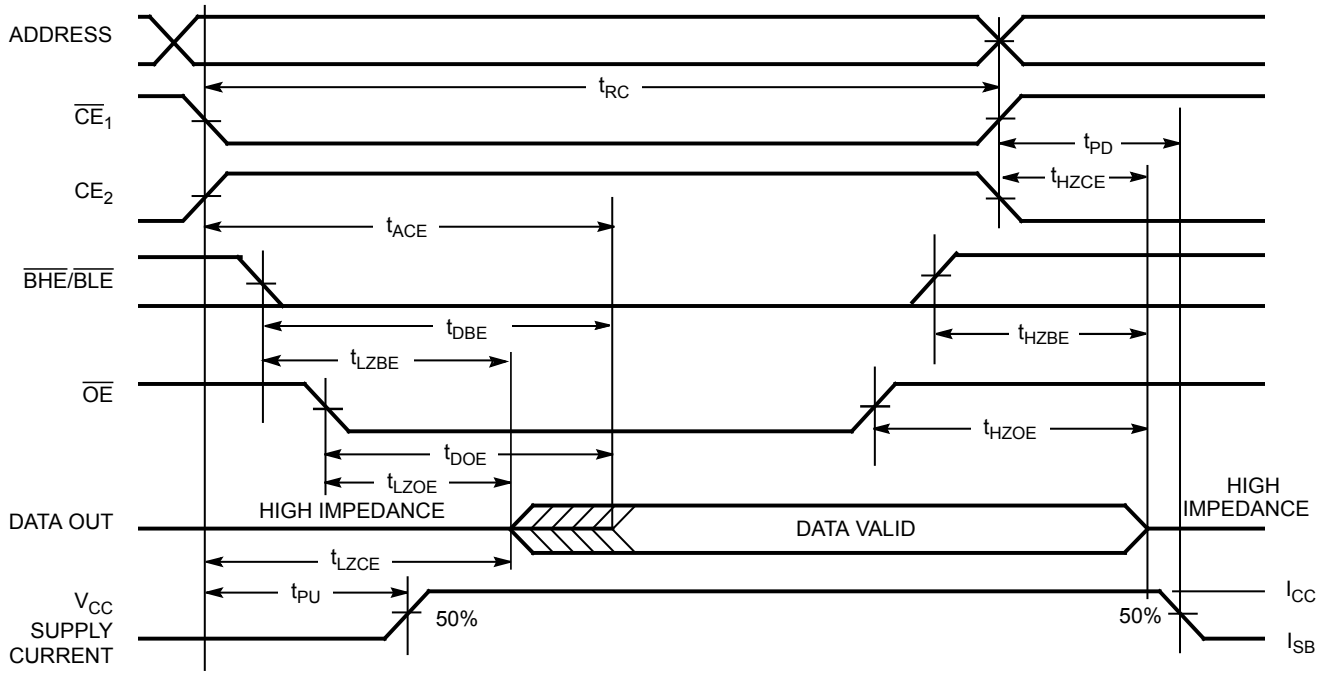


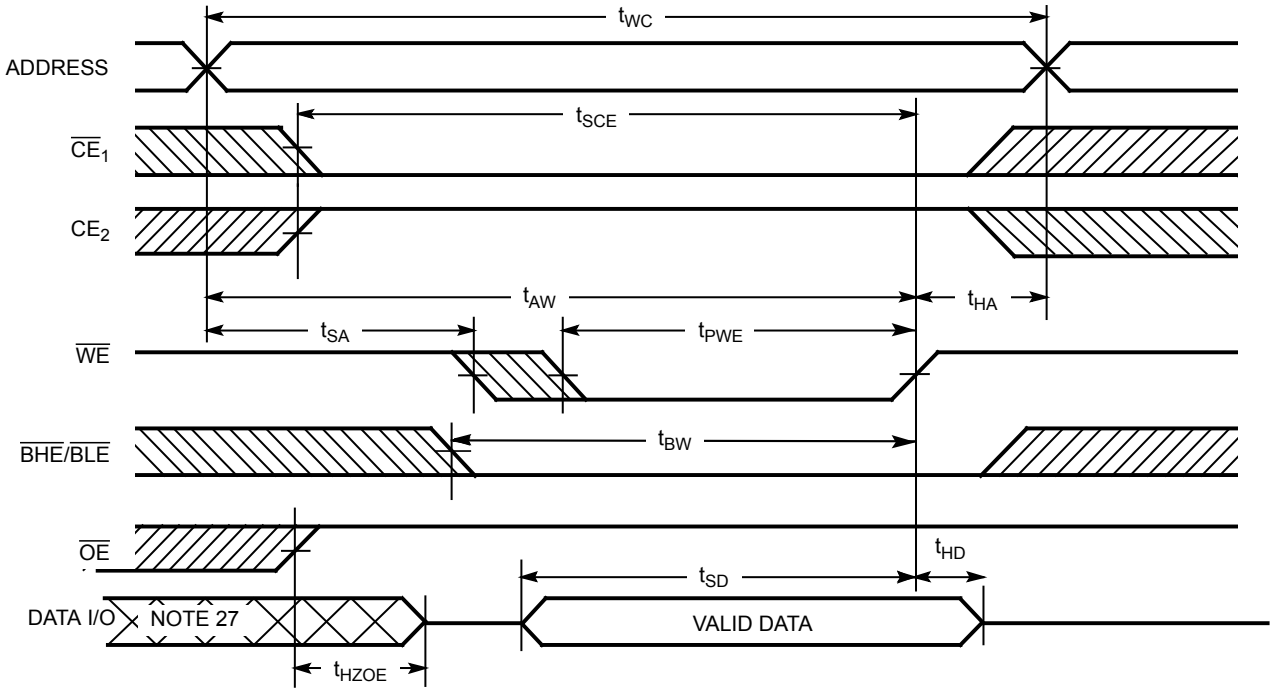
Figure 6. Read Cycle No. 2 ($\overline{OE}$ Controlled) [22, 23]



Notes
21. The device is continuously selected. $\overline{OE}$, $\overline{CE}_1 = V_{IL}$, $\overline{BHE}$, $\overline{BLE}$ or both $= V_{IL}$, and $CE_2 = V_{IH}$.
22. $\overline{WE}$ is HIGH for read cycle.
23. Address valid before or similar to $\overline{CE}_1$, $\overline{BHE}$, $\overline{BLE}$ transition LOW and CE_2 transition HIGH.

Switching Waveforms (continued)

Figure 7. Write Cycle No. 1 ($\overline{WE}$ Controlled) [24, 25, 26]

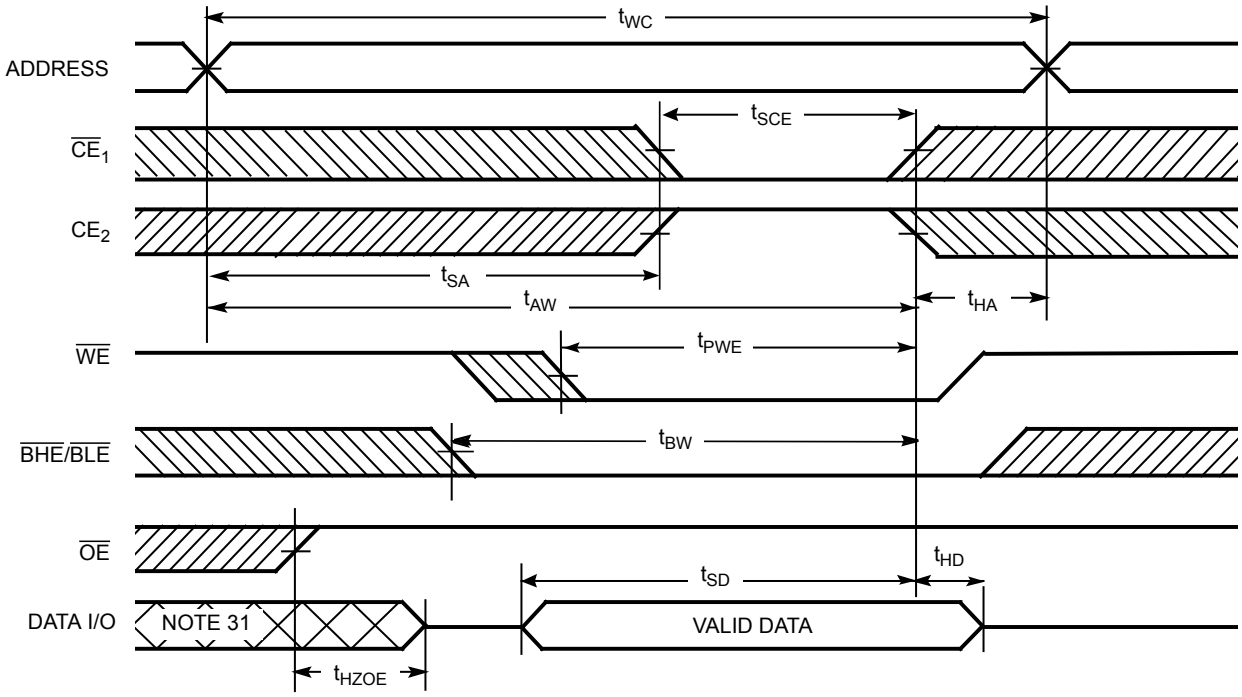


Notes

24. The internal write time of the memory is defined by the overlap of $\overline{WE}$, $\overline{CE}_1$ = V_{IL}, $\overline{BHE}$, $\overline{BLE}$, or both = V_{IL}, and CE_2 = V_{IH}. All signals must be active to initiate a write and any of these signals can terminate a write by going inactive. The data input setup and hold timing must be referenced to the edge of the signal that terminates the write.
25. Data I/O is high impedance if $\overline{OE}$ = V_{IH}.
26. If $\overline{CE}_1$ goes HIGH and CE_2 goes LOW simultaneously with $\overline{WE}$ = V_{IH}, the output remains in a high impedance state.
27. During this period, the I/Os are in output state. Do not apply input signals.

Switching Waveforms (continued)

Figure 8. Write Cycle No. 2 ($\overline{CE}_1$ or CE_2 Controlled) [28, 29, 30]



Notes

28. The internal write time of the memory is defined by the overlap of $\overline{WE}$, $\overline{CE}_1$ = V_{IL}, $\overline{BHE}$, $\overline{BLE}$, or both = V_{IL}, and CE_2 = V_{IH}. All signals must be active to initiate a write and any of these signals can terminate a write by going inactive. The data input setup and hold timing must be referenced to the edge of the signal that terminates the write.
29. Data I/O is high impedance if $\overline{OE}$ = V_{IH}.
30. If $\overline{CE}_1$ goes HIGH and CE_2 goes LOW simultaneously with $\overline{WE}$ = V_{IH}, the output remains in a high impedance state.
31. During this period, the I/Os are in output state. Do not apply input signals.

Switching Waveforms (continued)

Figure 9. Write Cycle No. 3 (WE Controlled, OE LOW) [32]

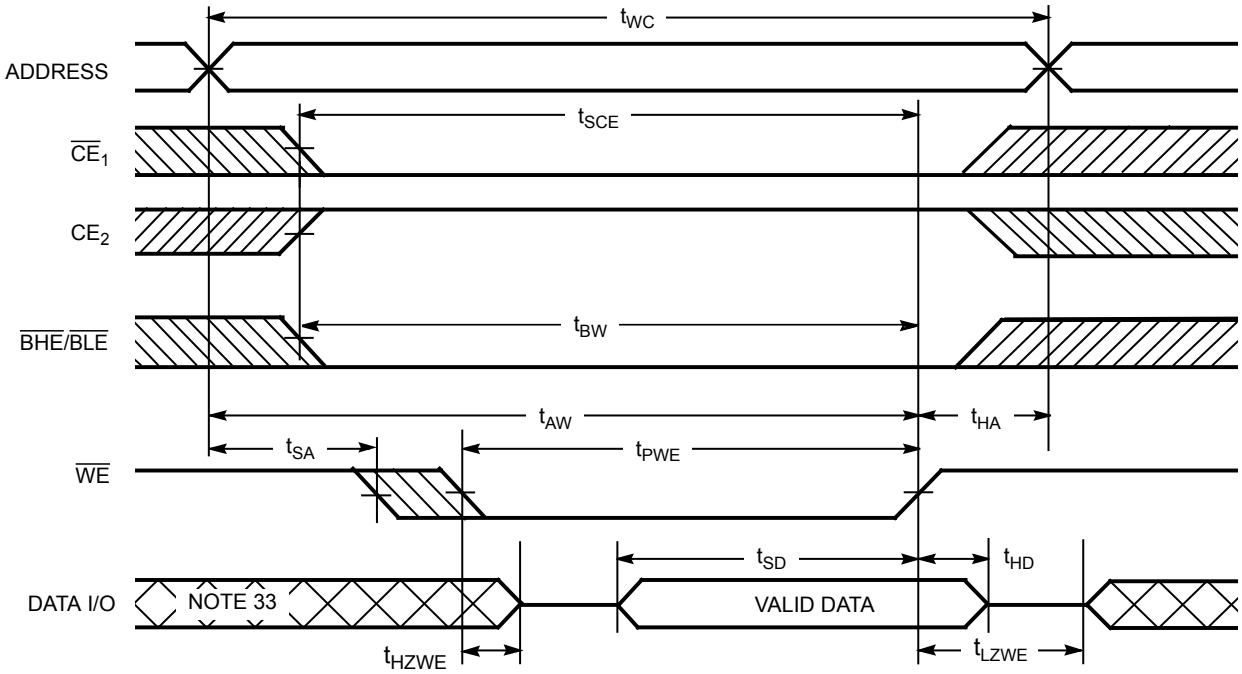
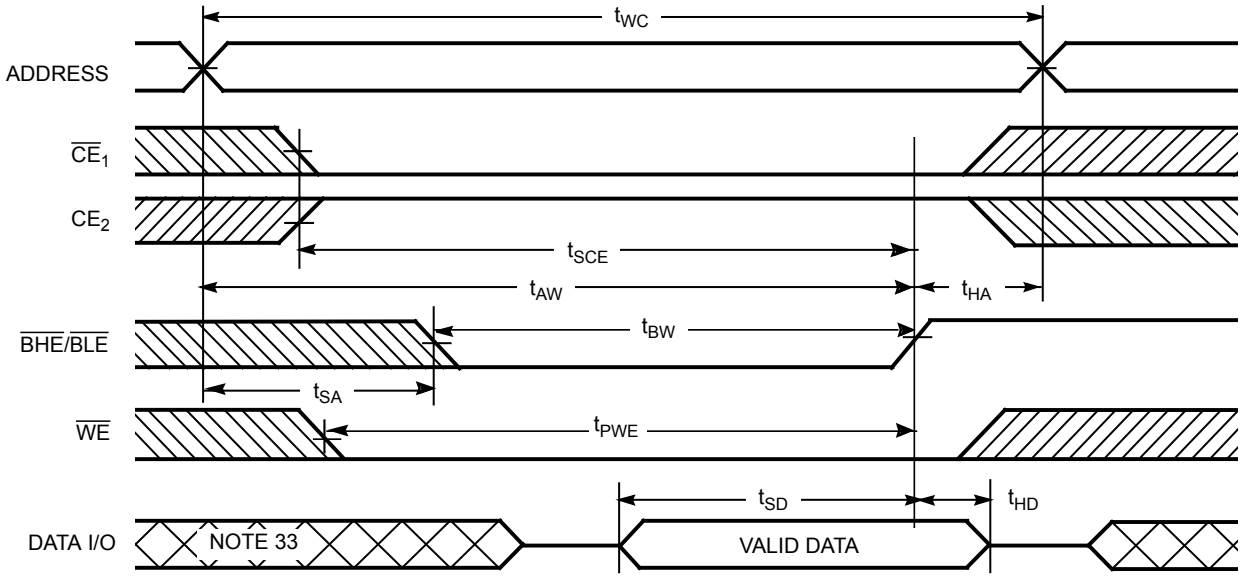


Figure 10. Write Cycle No. 4 (BHE/BLE Controlled, OE LOW) [32]



Notes
32. If $\overline{CE}_1$ goes HIGH and CE_2 goes LOW simultaneously with $\overline{WE}$ = V_{IH}, the output remains in a high impedance state.
33. During this period, the I/Os are in output state. Do not apply input signals.

Truth Table

$\overline{CE_1}$	CE_2	$\overline{WE}$	$\overline{OE}$	$\overline{BHE}$	$\overline{BLE}$	Inputs/Outputs	Mode	Power
H	X[34]	X	X	X	X	High Z	Deselect/Power Down	Standby (I_{SB})
X[34]	L	X	X	X	X	High Z	Deselect/Power Down	Standby (I_{SB})
X[34]	X[34]	X	X	H	H	High Z	Deselect/Power Down	Standby (I_{SB})
L	H	H	L	L	L	Data Out (I/O_0–I/O_{15})	Read	Active (I_{CC})
L	H	H	L	H	L	Data Out (I/O_0–I/O_7); High Z (I/O_8–I/O_{15})	Read	Active (I_{CC})
L	H	H	L	L	H	High Z (I/O_0–I/O_7); Data Out (I/O_8–I/O_{15})	Read	Active (I_{CC})
L	H	H	H	L	H	High Z	Output Disabled	Active (I_{CC})
L	H	H	H	H	L	High Z	Output Disabled	Active (I_{CC})
L	H	H	H	L	L	High Z	Output Disabled	Active (I_{CC})
L	H	L	X	L	L	Data In (I/O_0–I/O_{15})	Write	Active (I_{CC})
L	H	L	X	H	L	Data In (I/O_0–I/O_7); High Z (I/O_8–I/O_{15})	Write	Active (I_{CC})
L	H	L	X	L	H	High Z (I/O_0–I/O_7); Data In (I/O_8–I/O_{15})	Write	Active (I_{CC})

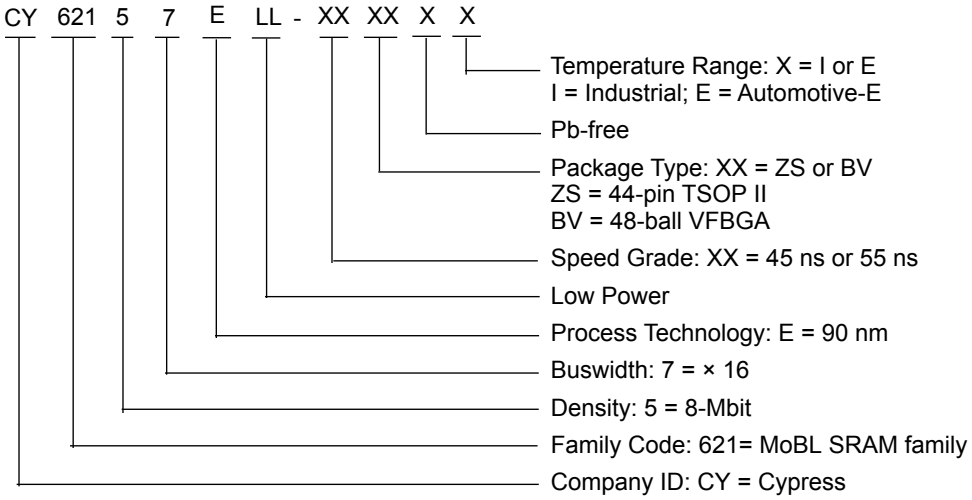
Note
34. The 'X' (Don't care) state for the Chip enables in the truth table refer to the logic state (either HIGH or LOW). Intermediate voltage levels on these pins is not permitted.

Ordering Information

Speed (ns)	Ordering Code	Package Diagram	Package Type	Operating Range
45	CY62157ELL-45ZSXI	51-85087	44-pin TSOP Type II (Pb-free)	Industrial
55	CY62157ELL-55ZSXE	51-85087	44-pin TSOP Type II (Pb-free)	Automotive
	CY62157ELL-55BVXE	51-85150	48-ball VFBGA (Pb-free)	

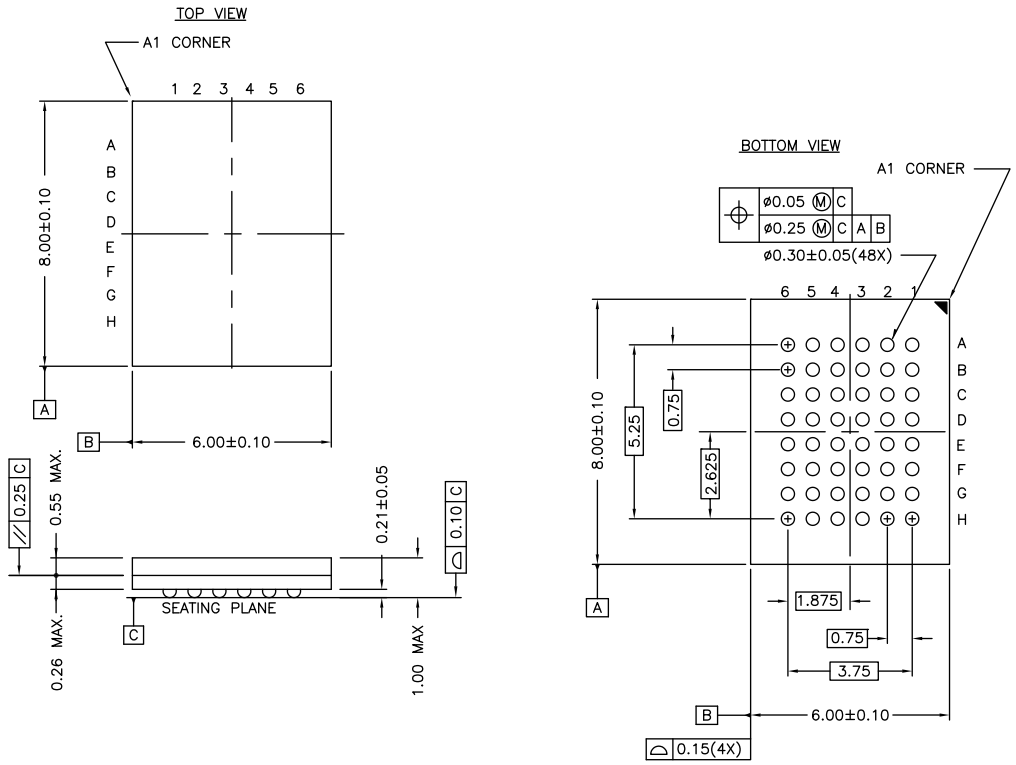
Contact your local Cypress sales representative for availability of these parts.

Ordering Code Definitions



Package Diagrams

Figure 11. 48-ball VFBGA (6 × 8 × 1.0 mm) BV48/BZ48 Package Outline, 51-85150

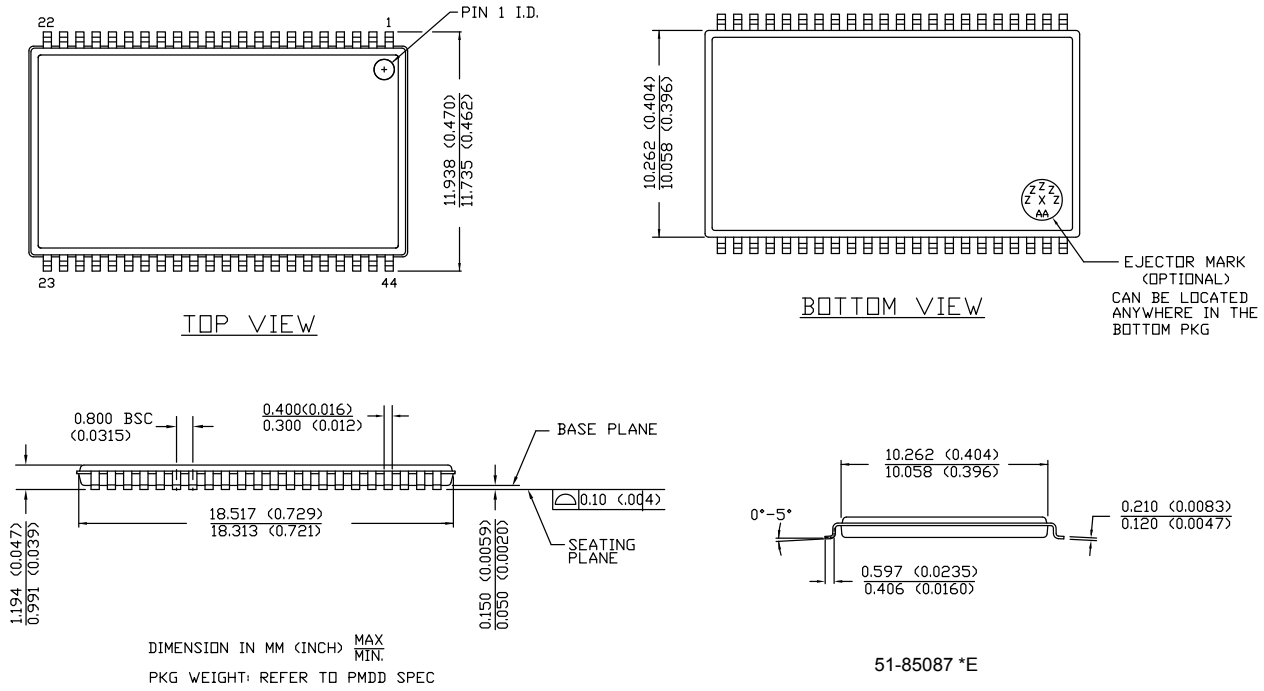


NOTE:
PACKAGE WEIGHT: See Cypress Package Material Declaration Datasheet (PMDD) posted on the Cypress web.

51-85150 *H

Package Diagrams (continued)

Figure 12. 44-pin TSOP Z44-II Package Outline, 51-85087



Acronyms

Acronym	Description
$\overline{CE}$	Chip Enable
CMOS	Complementary Metal Oxide Semiconductor
I/O	Input/Output
$\overline{OE}$	Output Enable
RAM	Random Access Memory
SRAM	Static Random Access Memory
TTL	Transistor-Transistor Logic
TSOP	Thin Small Outline Package
VFBGA	Very Fine-Pitch Ball Grid Array
$\overline{WE}$	Write Enable

Document Conventions

Units of Measure

Symbol	Unit of Measure
°C	degree Celsius
MHz	megahertz
µA	microampere
µs	microsecond
mA	milliampere
mm	millimeter
ns	nanosecond
Ω	ohm
%	percent
pF	picofarad
V	volt
W	watt

Document History Page

Document Title: CY62157E MoBL®, 8-Mbit (512 K × 16) Static RAM Document Number: 38-05695				
Rev.	**ECN No.**	**Issue Date**	**Orig. of Change**	**Description of Change**
**	291273	See ECN	PCI	New data sheet.
*A	457689	See ECN	NXR	Added Automotive Product Removed Industrial Product Removed 35 ns and 45 ns speed bins Removed “L” bin Updated AC Test Loads table Corrected t_R in Data Retention Characteristics from 100 µs to t_{RC} ns Updated the Ordering Information and replaced the Package Name column with Package Diagram
*B	467033	See ECN	NXR	Added Industrial Product (Final Information) Removed 48 ball VFBGA package and its relevant information Changed the $I_{CC(typ)}$ value of Automotive from 2 mA to 1.8 mA for f = 1MHz Changed the $I_{SB2(typ)}$ value of Automotive from 5 µA to 1.8 µA Modified footnote #4 to include current limit Updated the Ordering Information table
*C	569114	See ECN	VKN	Added 48 ball VFBGA package Updated Logic Block Diagram Added footnote #3 Updated the Ordering Information table
*D	925501	See ECN	VKN	Added footnote #9 related to I_{SB2} and I_{CCDR} Added footnote #14 related AC timing parameters
*E	1045801	See ECN	VKN	Converted Automotive specs from preliminary to final
*F	2934396	06/03/10	VKN	Added footnote #23 related to chip enable Updated package diagrams Updated template.
*G	3110053	12/14/2010	PRAS	Changed Table Footnotes to Footnotes. Added Ordering Code Definitions.
*H	3269641	05/30/2011	RAME	Removed the note “For best practice recommendations, please refer to the Cypress application note AN1064, SRAM System Guidelines.” and its reference in Functional Description. Updated Electrical Characteristics. Updated Data Retention Characteristics. Added Acronyms and Units of Measure. Updated in new template.
*I	4013958	06/05/2013	MEMJ	Updated Functional Description. Updated Electrical Characteristics: Added one more Test Condition “V_{CC} = 5.5 V, I_{OH} = –0.1 mA” for V_{OH} parameter and added maximum value corresponding to that Test Condition. Added Note 8 and referred the same note in maximum value for V_{OH} parameter corresponding to Test Condition “V_{CC} = 5.5 V, I_{OH} = –0.1 mA”. Updated Package Diagrams: spec 51-85150 – Changed revision from *F to *H. spec 51-85087 – Changed revision from *C to *E.
*J	4102449	08/22/2013	VINI	Updated Switching Characteristics: Updated Note 17. Updated in new template.

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